

<b>Notice of References Cited</b>	Application/Control No. 10/777,660	Applicant(s)/Patent Under Reexamination REIDELSTURZ ET AL.	
	Examiner Diego Herrera	Art Unit 2617	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0049037	04-2002	Christensen et al.	455/3.06
*	B	US-7,142,608	11-2006	Schulze et al.	375/260
*	C	US-6,870,487	03-2005	Nuesser et al.	340/901
*	D	US-2002/0152267	10-2002	Lennon, Alison J.	709/203
*	E	US-2003/0005433	01-2003	Janik et al.	725/18
*	F	US-2003/0040302	02-2003	Okada, Hiroki	455/414
*	G	US-2003/0100337	05-2003	Chotkowski et al.	455/556
*	H	US-2003/0114145	06-2003	Boda et al.	455/412
*	I	US-2004/0203729	10-2004	Makipaa et al.	455/426.1
*	J	US-5,832,223	11-1998	Hara et al.	725/114
*	K	US-2004/0192211	09-2004	Gallagher et al.	455/067.11
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.